

# Device Modeling Report

COMPONENTS:THYRISTOR  
PART NUMBER:MCR225-4FP  
MANUFACTURER: MOTOROLA SEMICONDUCTOR



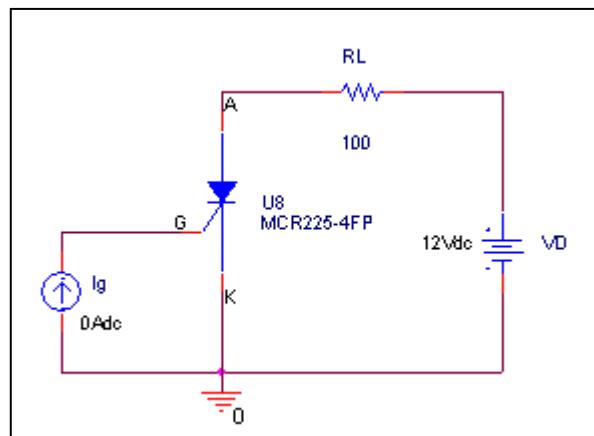
**Bee Technologies Inc.**

## DIODE MODEL

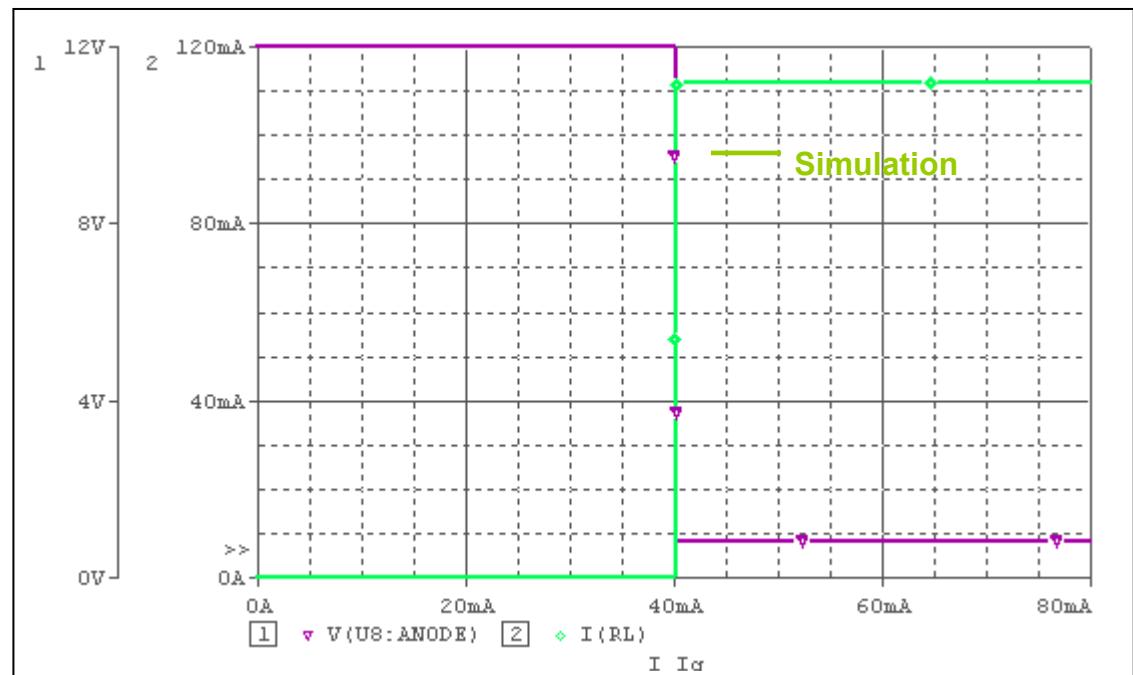
Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## IG-VT Characteristic

Evaluation Circuit



Simulation result



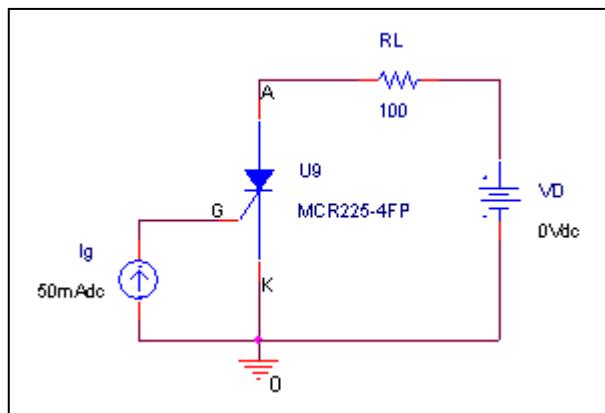
Comparison Table

	Measurement	Simulation	% Error
I <sub>G<sub>T</sub></sub> (mA)	40(max)	40	0
V <sub>G<sub>T</sub></sub> (V)	0.8	0.799504	-0.06200

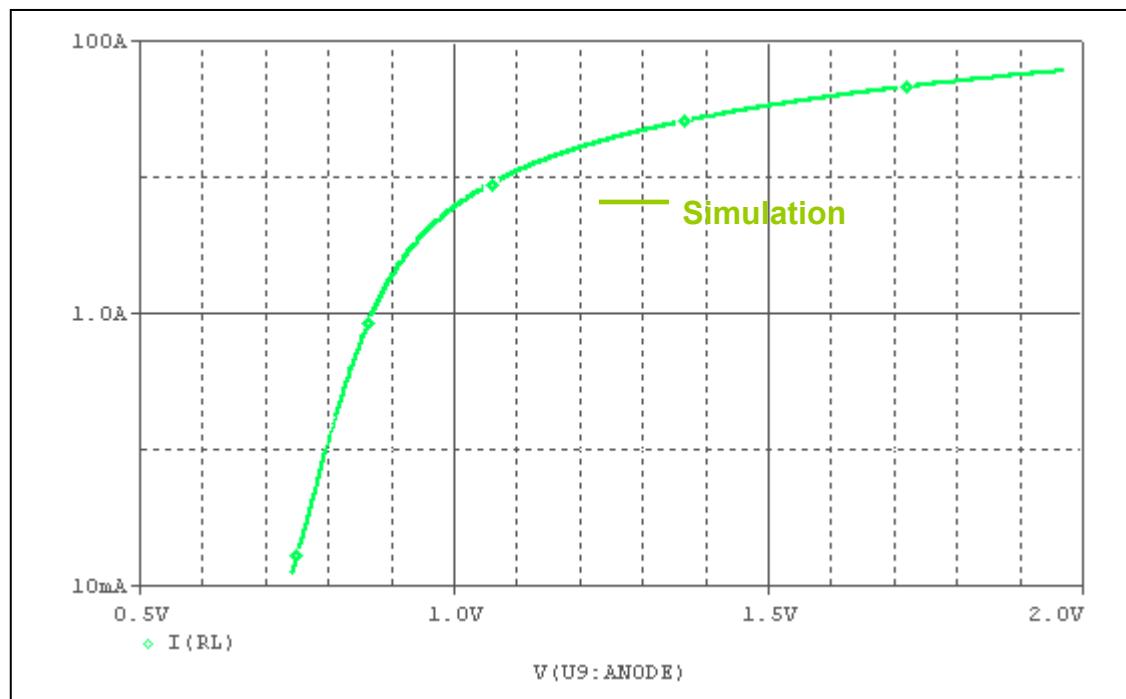
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## ITM-VTM Characteristic

Evaluation Circuit



Simulation result

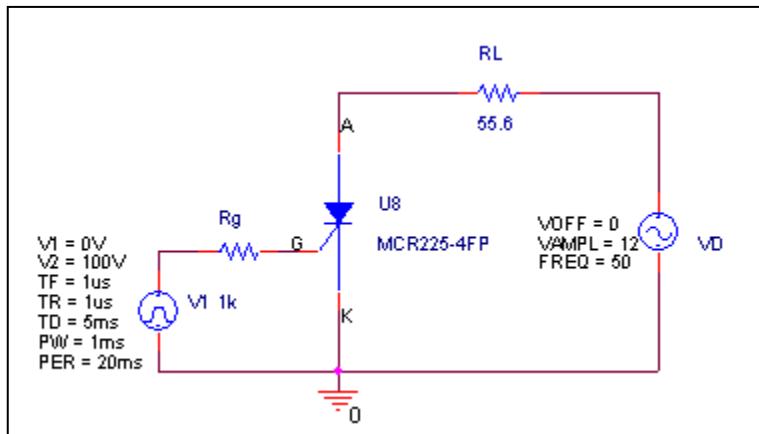


Comparison Table

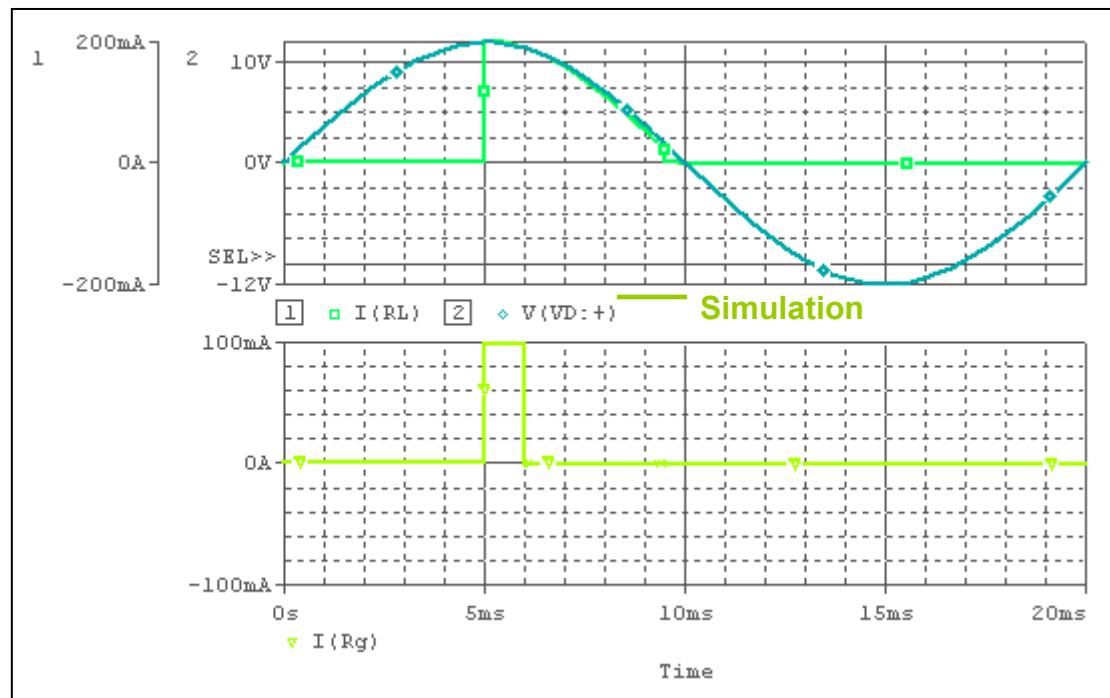
At ITM=50A	Measurement	Simulation	% Error
VTM(V)	1.8(max)	1.7969	-0.17222

## Holding Characteristic (IH)

### Evaluation Circuit



### Simulation result

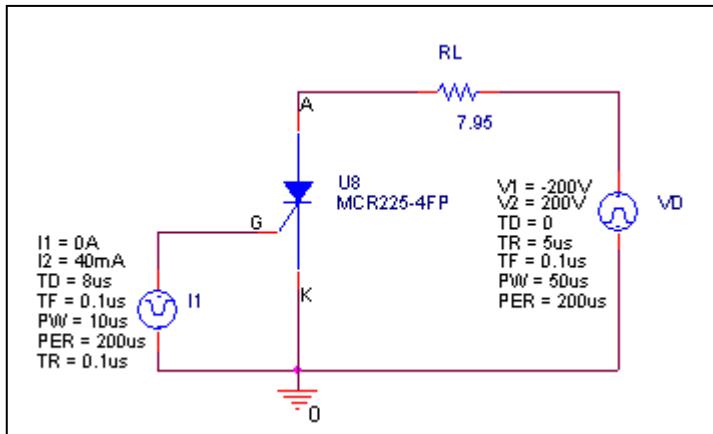


### Comparison Table

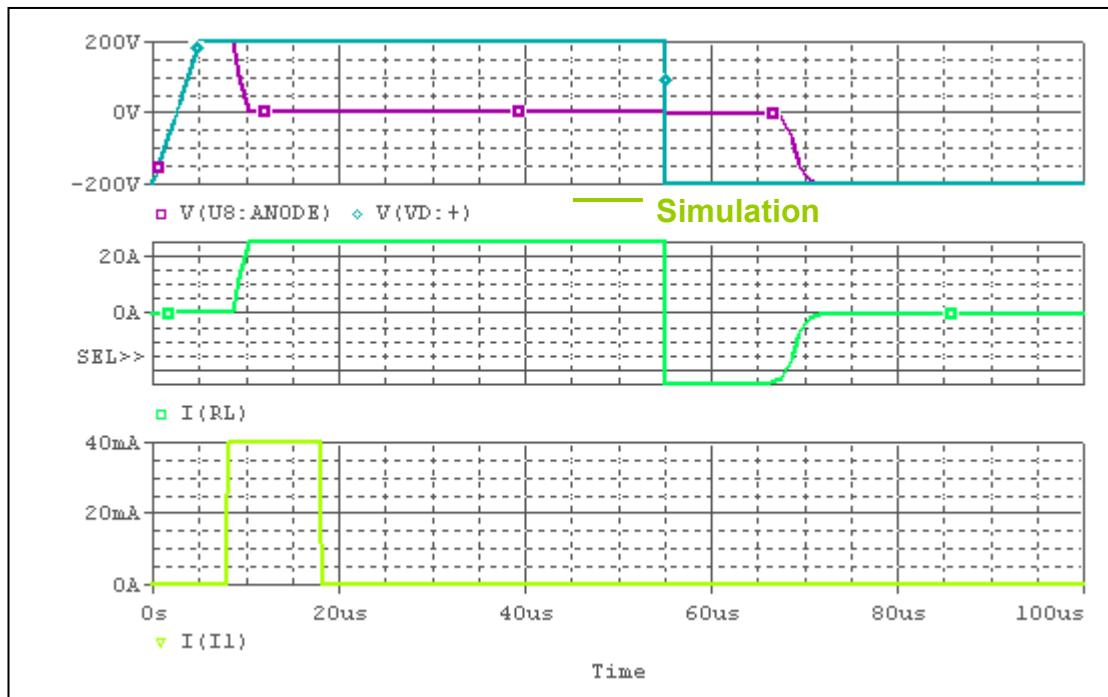
<b>VD=12V</b>	<b>Measurement</b>	<b>Simulation</b>	<b>% Error</b>
<b>IH(mA)</b>	<b>20</b>	<b>20.049</b>	<b>0.24500</b>

## Switching Time Characteristic

Evaluation Circuit



Simulation result



Comparison Table

	Measurement	Simulation	%Error
Ton(us)	1.5	1.4600	-2.66667
Toff(us)	15	15.299	1.99333